

Docket No.: SON-2628
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Shinji Omori et al

Application No.: Not Yet Assigned

Confirmation No.:

Filed: September 24, 2004

Art Unit: N/A

For: MASK PATTERN CORRECTION METHOD, Examiner: Not Yet Assigned
PRODUCTION METHOD OF
SEMICONDUCTOR DEVICE, MASK
PRODUCTION METHOD AND MASK

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the requirements of 37 CFR §§ 1.56 and MPEP 609, applicant through his attorneys and representatives, hereby brings to the attention of the Examiner the references noted on the attached Form PTO-1449, copies of which are enclosed.

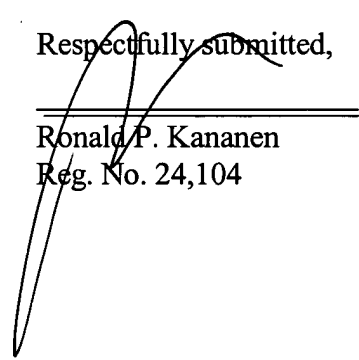
The references are cited in the International Search Report of applicant's corresponding PCT Application No. PCT/JP03/03455 a copy of which is enclosed.

It is requested that the Examiner review the references noted and make such consideration of record.

Dated: September 24, 2004

Rader, Fishman & Grauer PLLC
1233 20th Street
Washington, D.C. 20036
Telephone: (202) 955-3750
Facsimile: (202) 955-3751
Customer No. 23353

Respectfully submitted,



Ronald P. Kananen
Reg. No. 24,104

Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete If Known	
				Application Number	Not Yet Assigned 10/509230
				Filing Date	September 24, 2004
				First Named Inventor	Shinji Omori
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	SON-2628

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	5,831,272	11/3/98	Utsumi	
	AB	2001/0049811 A1	12/6/01	Taoka	
	AC	2002/0000524 A1	01/03/02	Suzuki et al	
	AD				

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	BA	JP 8-203817	08/09/96	Nippon Telegr & Teleph Corp.		<input checked="" type="checkbox"/>
	BB	JP 11-135423	05/21/99	Utsumi		<input checked="" type="checkbox"/>
	BC	JP 2001-23880	01/26/01	Sony Corp.		<input checked="" type="checkbox"/>
	BD	JP 11-305416	11/05/99	Hitachi Ltd.		<input checked="" type="checkbox"/>
	BE	JP 9-218032	02/14/96	Nippon Telegr & Teleph Corp.		<input checked="" type="checkbox"/>
	BF	JP 2001-265012	09/28/01	Nippon Telegr & Teleph Corp.		<input checked="" type="checkbox"/>
	BG	JP 2001-350250	12/21/01	Mitsubishi Electric Corp.		<input checked="" type="checkbox"/>
	BH	JP 2001-351854	12/21/01	Nikon Corp.		<input checked="" type="checkbox"/>
	BI					
	BJ					
	BK					
	BL					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	International Search Report dated July 8, 2003	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
--------------------	--	-----------------	--